

<b>Notice of References Cited</b>	Application/Control No. 10/571,058		Applicant(s)/Patent Under Reexamination IWAMA ET AL.	
	Examiner NATHANIEL J. LEE		Art Unit 4126	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,414,434 B1	07-2002	Nakano et al.	313/582
*	B	US-5,341,065	08-1994	Uemura et al.	313/495
*	C	US-2002/0003406 A1	01-2002	Kang et al.	313/587
*	D	US-6,666,992 B2	12-2003	Feldmann et al.	252/301.4R
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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